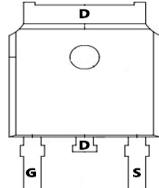
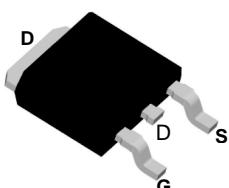
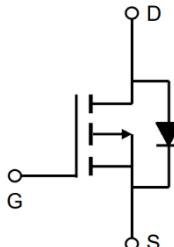


TM80P02D

P -Channel Enhancement Mosfet

<p>General Description</p> <ul style="list-style-type: none"> • Low $R_{DS(ON)}$ • RoHS and Halogen-Free Compliant <p>Applications</p> <ul style="list-style-type: none"> • Load switch • PWM 	<p>General Features</p> <p>$V_{DS} = -20V$ $I_D = -80A$</p> <p>$R_{DS(ON)} = 4.5\text{ m}\Omega$ (typ.) @ $V_{GS} = -4.5V$</p> <p>100% UIS Tested 100% R_g Tested</p> 
 <p>D:TO-252-3L</p>  <p>Marking: 80P02</p>	

Absolute Maximum Ratings (TC=25°C unless otherwise noted)				
Parameter	Symbol	Value	Unit	
Drain-Source Voltage	V_{DS}	-20	V	
Gate-Source Voltage	V_{GS}	± 12	V	
Continuous Drain Current	I_D	-80	A	
		-52		
Pulsed Drain Current ¹	I_{DM}	-296	A	
Single Pulse Avalanche Energy ²	E_{AS}	80	mJ	
Total Power Dissipation	P_D	43.1	W	
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C	
Thermal Data				
Parameter	Symbol	Value	Unit	
Thermal Resistance from Junction-to-Ambient ³	$R_{\theta JA}$	65	°C/W	
Thermal Resistance from Junction-to-Case	$R_{\theta JC}$	2.9	°C/W	

TM80P02D
P -Channel Enhancement Mosfet
Electrical Characteristics ($T_J = 25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-20	-	-	V
Gate-body Leakage current	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 12V$	-	-	± 100	nA
Zero Gate Voltage Drain Current $T_J=25^\circ\text{C}$	I_{DSS}	$V_{DS} = -20V, V_{GS} = 0V$	-	-	-1	μA
$T_J=100^\circ\text{C}$			-	-	-100	
Gate-Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.4	-0.7	-1	V
Drain-Source On-Resistance ⁴	$R_{DS(\text{on})}$	$V_{GS} = -4.5V, I_D = -10\text{A}$	-	4.5	5.4	$\text{m}\Omega$
		$V_{GS} = -2.5V, I_D = -10\text{A}$	-	5.5	6.9	
Forward Transconductance ⁴	g_{fs}	$V_{DS} = -4.5V, I_D = -10\text{A}$	-	56	-	S
Dynamic Characteristics⁵						
Input Capacitance	C_{iss}	$V_{DS} = -10V, V_{GS} = 0V, f = 1\text{MHz}$	-	4770	-	pF
Output Capacitance	C_{oss}		-	665	-	
Reverse Transfer Capacitance	C_{rss}		-	570	-	
Gate Resistance	R_g	f = 1MHz	-	9.6	-	Ω
Switching Characteristics⁵						
Total Gate Charge	Q_g	$V_{GS} = -4.5V, V_{DS} = -10V, I_D = -10\text{A}$	-	55	-	nC
Gate-Source Charge	Q_{gs}		-	5.2	-	
Gate-Drain Charge	Q_{gd}		-	10	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = -4.5V, V_{DD} = -10V, R_G = 3\Omega, I_D = -10\text{A}$	-	22	-	ns
Rise Time	t_r		-	38	-	
Turn-Off Delay Time	$t_{d(off)}$		-	110	-	
Fall Time	t_f		-	62	-	
Drain-Source Body Diode Characteristics						
Diode Forward Voltage ⁴	V_{SD}	$I_S = -10\text{A}, V_{GS} = 0V$	-	-	-1.2	V
Continuous Source Current	I_S	-	-	-	-80	A

Note :

1. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$.
2. The EAS data shows Max. rating. The test condition is $V_{DD} = -25V, V_{GS} = -10V, L = 0.4\text{mH}, I_{AS} = -20\text{A}$.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed, pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.

Typical Characteristics

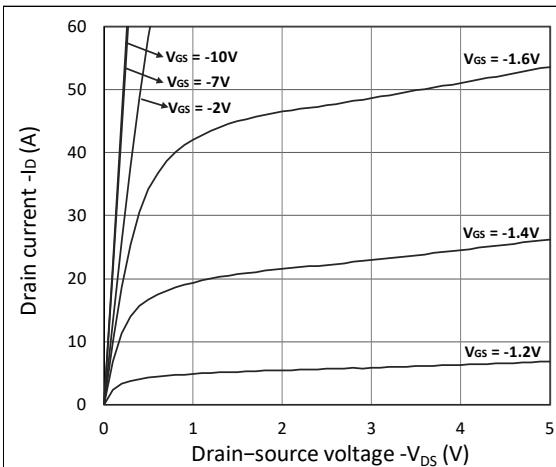


Figure 1. Output Characteristics

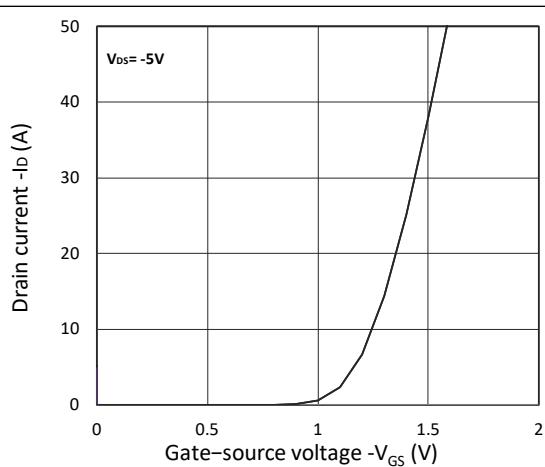


Figure 2. Transfer Characteristics

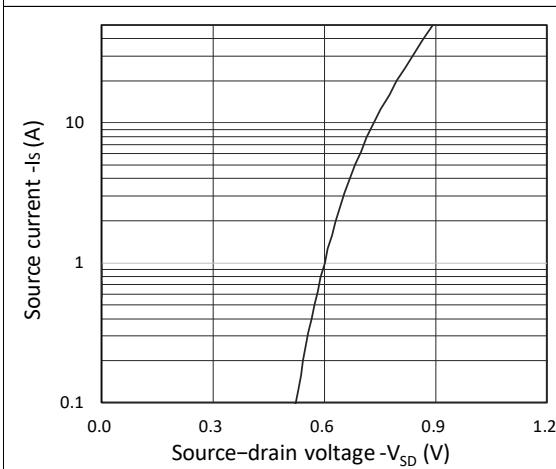


Figure 3. Forward Characteristics of Reverse

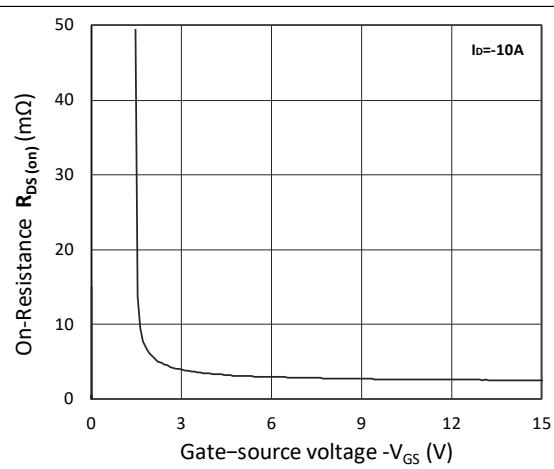


Figure 4. R_{DS(ON)} vs. V_{GS}

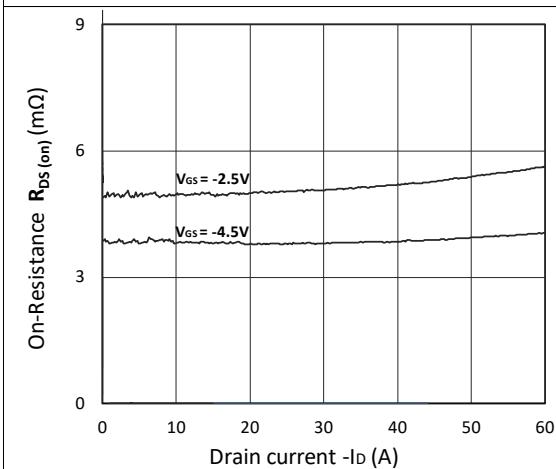


Figure 5. R_{DS(ON)} vs. I_D

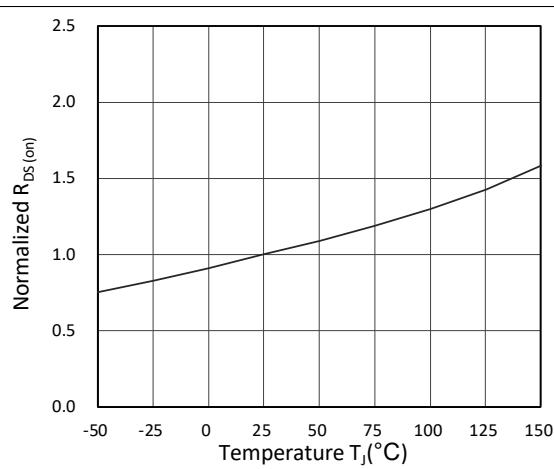


Figure 6. Normalized R_{DS(ON)} vs. Temperature

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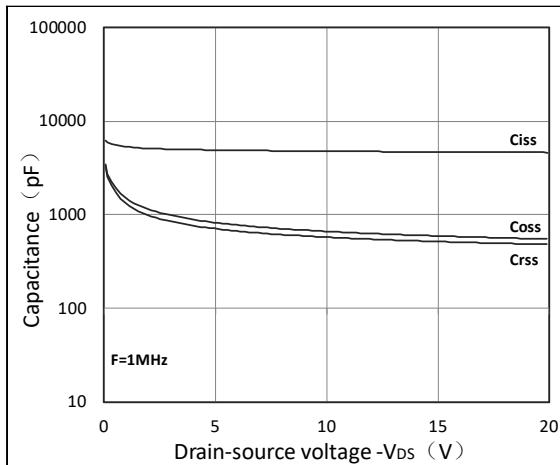


Figure 7. Capacitance Characteristics

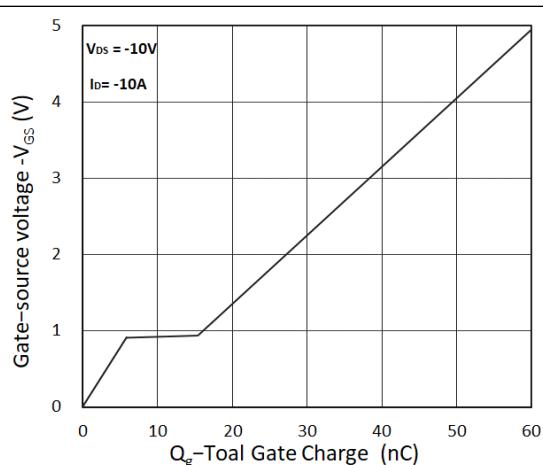


Figure 8. Gate Charge Characteristics

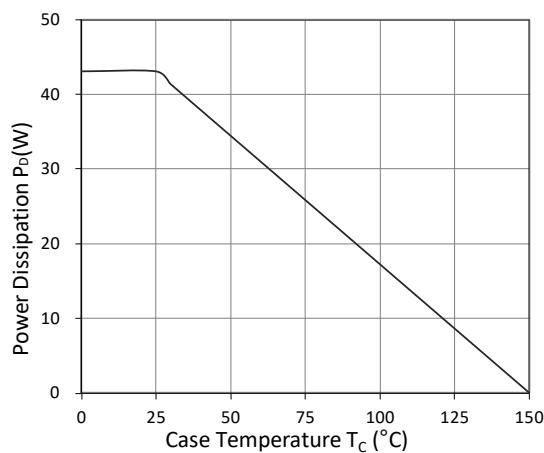


Figure 9. Power Dissipation

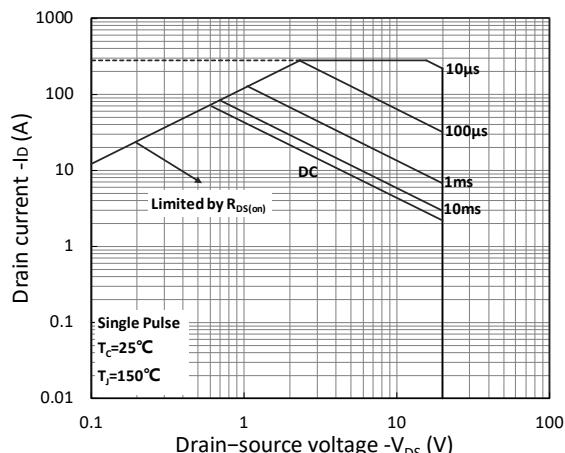


Figure 10. Safe Operating Area

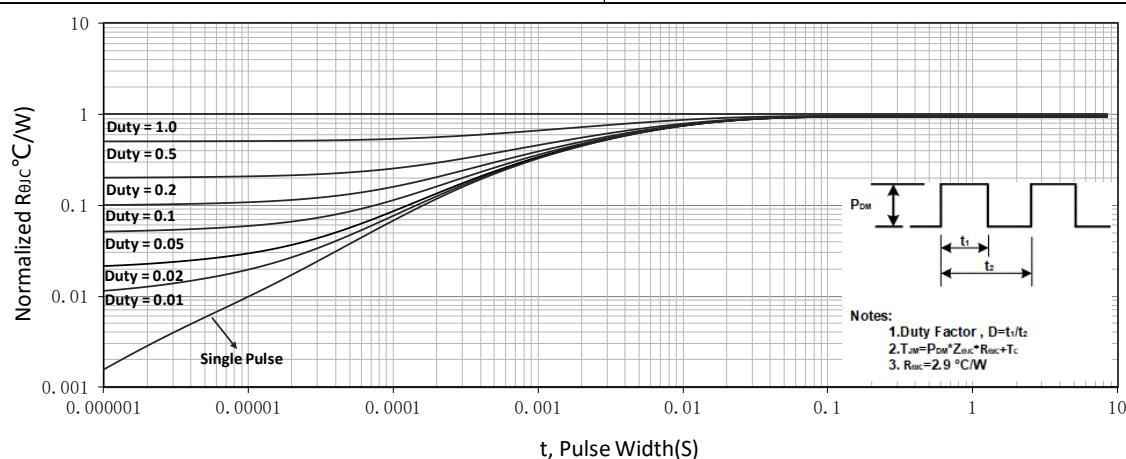
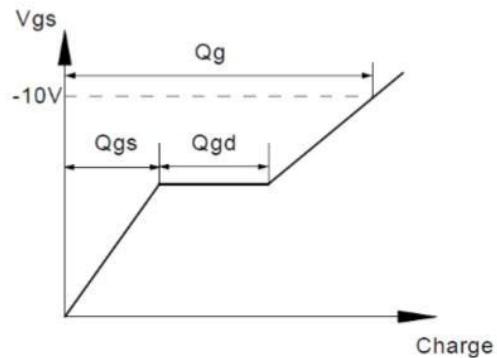
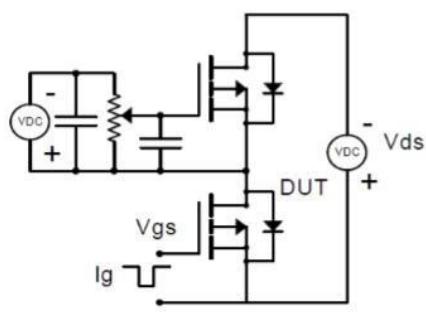


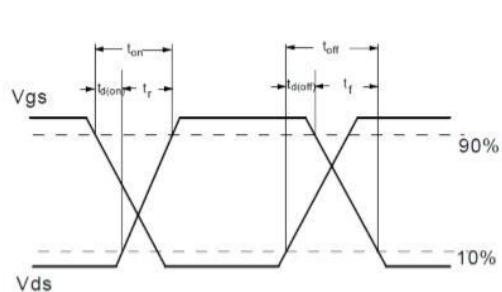
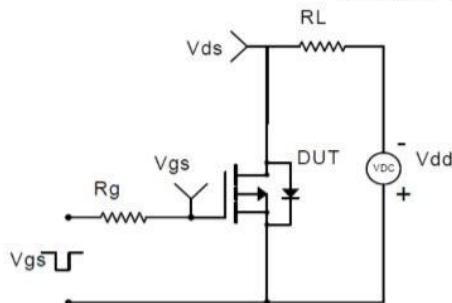
Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

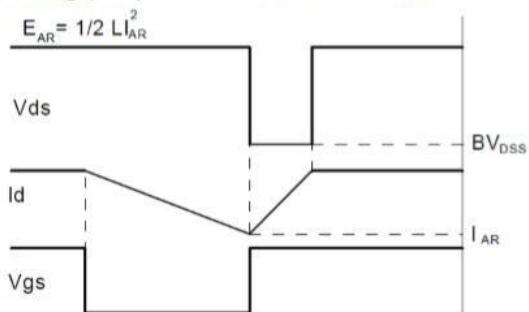
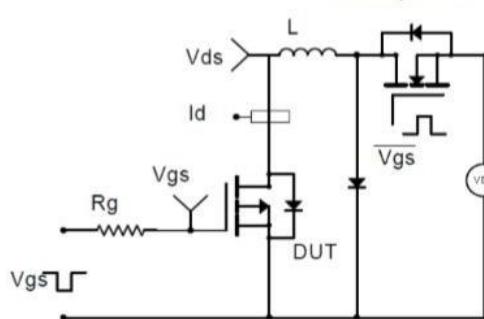
Gate Charge Test Circuit & Waveform



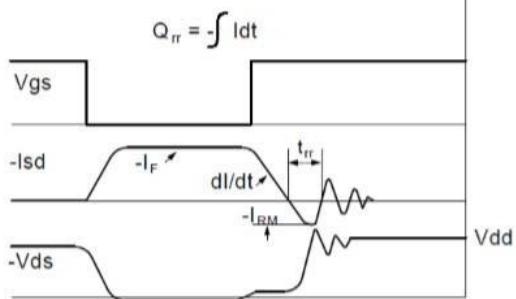
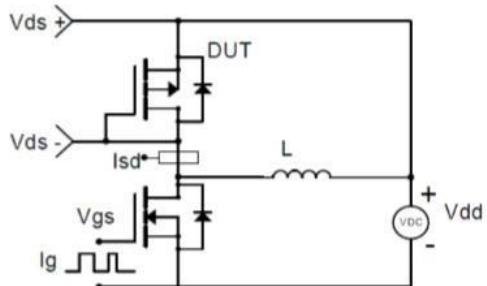
Resistive Switching Test Circuit & Waveforms



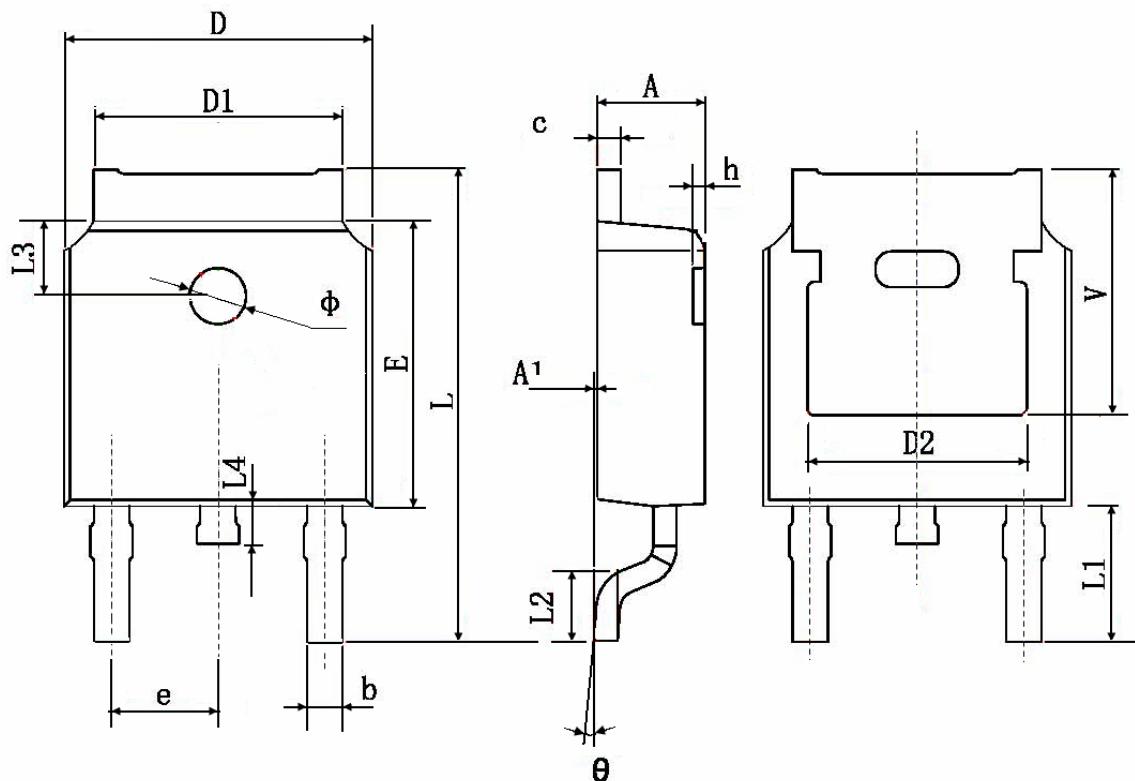
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Mechanical Data: TO-252-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	